



Device Test Report

Device Test System Revision : 3.1.0.6 Build: 2020-3-12 Test ID:692290203



Vendor : Banner Engineering Corporation

Vendor ID : 0x01C3

IO-Link Version : 1.1

ISDU supported : True

Process Data Input Bits : 0

Min Cycle Time : 20000 μ s

Implemented Access Locks :

parameter="True" datastorage="True" localParameterization="False" localUserInterface="False"

IODD : Banner_Engineering-CL50RGBIOL-20210903-IODD1.1.xml

Checker : IODD-Checker V1.1.4

Firmware Revision : 1.0.23413

Device Name : CL50 Pro with IO-Link Q

Device ID : 0x06000D

Product ID : CL50PS*KQ

SIO mode supported : False

Process Data Output Bits : 104

Bitrate : COM2

CRC : 2071939469

Hardware Revision : V00-01

Test result : All test were passed with positiv result in complete operation

Test operated by :

Company : _____

Name : _____

Testreport : Test Configuration

Test variable for 8 Bit index access :

Index : 244

Length: 1

Data (hex) : 00

Test variable for 16 Bit index access :

Index : 257

Length: 1

Data (hex) : 01

Test variable for 8 Bit index extended length :

Index : 16368

Length: 16

Data (hex) : 20 20 20 20 20 20 20 20 20 20 20 20 20 20 20 20

Implemented system commands :

1 2 3 4 5 6 130

M-sequence Capability (hex) :

09

Commands to generate events :

Index : 16376

Event trigger 1 : appear value = 0

disappear value = 1

Event trigger 2 : appear value = 2

disappear value = 3

==== Config Messages from Testcases =====

The testcase is skipped because the device is not capable to change a parameter via local user interface

Testreport Overview (3)

SDCI_TC_0120 TCD_DLIC_DEFP_HARDREV	ok
SDCI_TC_0121 TCD_DLIC_DEFP_FIRMREV	ok
SDCI_TC_0122 TCD_DLIC_DEFP_TAGVALID	ok
SDCI_TC_0123 TCD_DLIC_DEFP_TAGINVALID	ok
SDCI_TC_0124 TCD_DLIC_DEFP_ERRCOUNT	ok
SDCI_TC_0128 TCD_DLIC_DEFP_DEVSTAT	ok
SDCI_TC_0129 TCD_DLIC_DEFP_DETAILDEVSTAT	ok
SDCI_TC_0130 TCD_DLIC_DEFP_DETAILDEVSTATINACTIVE	ok
SDCI_TC_0131 TCD_DLIC_DEFP_DETAILDEVSTATACTIVE	ok
SDCI_TC_0132 TCD_DLIC_DEFP_PDIN	ok
SDCI_TC_0133 TCD_DLIC_DEFP_PDOUT	ok
SDCI_TC_0134 TCD_DLIC_DEFP_OFFTIMEVALID	ok
SDCI_TC_0136 TCD_DLIC_DEFP_PROFILEPARREAD	ok
SDCI_TC_0137 TCD_DLIC_DEFP_PROFILEPARWRITE	ok
SDCI_TC_0140 TCD_DLIC_DEFP_WRITETOREADONLY	ok
SDCI_TC_0141 TCD_DLIC_DEFP_WRITETOOSHORT	ok
SDCI_TC_0142 TCD_DLIC_DEFP_WRITETOOLONG	ok
Block Parameter Tests V1.0.3.45	
SDCI_TC_0143 TCD_DSBP_APPL_BPDOWNLOAD	ok
SDCI_TC_0144 TCD_DSBP_APPL_BPBREAKCMD	ok
SDCI_TC_0145 TCD_DSBP_APPL_BPBREAKRESET	ok
SDCI_TC_0147 TCD_DSBP_APPL_BPBREAK2DOWNLOADS	ok
SDCI_TC_0148 TCD_DSBP_APPL_BPBREAKLOCALLOCK	ok
IODD based Tests V1.0.3.45	
SDCI_TC_0149 TCD_IODD_PARV_IDENT	ok
SDCI_TC_0150 TCD_IODD_PARV_COMPROFILE	ok
SDCI_TC_0151 TCD_IODD_PARV_READVERIFY	ok
SDCI_TC_0152 TCD_IODD_PARV_WRITEVERIFY	ok
SDCI_TC_0155 TCD_IODD_PARV_FACTORYSETTINGS	ok
SDCI_TC_0156 TCD_IODD_PARV_ACCESSLOCK	ok
SDCI_TC_0157 TCD_IODD_PARV_INDEXCONSISTENT	ok
support of Physical Layer Tests V1.0.3.45	
SDCI_TC_0304 TCD_PHYL_INTF_UARTTRANSDelay	skipped
SDCI_TC_0305 TCD_PHYL_INTF_RESPONSETIME	skipped

Test Report Statistics:

Number of test cases overall : 31
Number of test cases ok : 29
Number of test cases failed : 0
Number of test cases skipped : 2
Test Operation : complete